



Designation: E 1097 – 9703

## Standard Guide for Direct Current Plasma Emission Spectrometry Analysis<sup>1</sup>

This standard is issued under the fixed designation E 1097; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon ( $\epsilon$ ) indicates an editorial change since the last revision or reapproval.

### 1. Scope

1.1 This guide covers procedures for using a direct current argon plasma atomic emission spectrometer (DCP) to determine the concentration of elements in solution. Recommendations are provided for preparing and calibrating the instrument, assessing instrument performance, diagnosing and correcting for interferences, measuring test solutions, and calculating results. A method to correct for instrument drift is included.

1.2 This guide does not specify all the operating conditions for a ~~direct current plasma~~ DCP because of the differences between models of these instruments. Analysts should follow instructions provided by the manufacturer of the particular instrument.

1.3 This guide does not attempt to specify in detail all of the hardware components and computer software of the instrument. It is assumed that the instrument, whether commercially available, modified, or custom built, will be capable of performing the analyses for which it is intended, and that the analyst has verified this before performing the analysis.

1.4 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use.* Specific precautionary statements are given in Section 8.

---

<sup>1</sup> This guide is under the jurisdiction of ASTM Committee ~~E-1~~ E01 on Analytical Chemistry for Metals, Ores, and Related Materials and is the direct responsibility of Subcommittee E01.20 on General Analytical Practices.

Current edition approved Oct. ~~10, 1997~~, 1, 2003. Published ~~June 1998~~, Dec. 2003. Originally published as E-3 Proposal P152. Last previous edition approved in 1997 as E 1097 – 937.

## 2. Referenced Documents

### 2.1 ASTM Standards:<sup>2</sup>

- E 29 Practice for Using Significant Digits in Test Data to Determine Conformance with Specifications
- E 50 Practices for Apparatus, Reagents, and Safety Precautions for Chemical Analysis of Metals, Ores, and Related Materials
- E 135 Terminology Relating to Analytical Chemistry for Metals, Ores, and Related Materials
- E 743 Guide for Spectrochemical Laboratory Quality Assurance<sup>3</sup>
- E 876 Practice for Use of Statistics in the Evaluation of Spectrometric Data
- E 882 Guide for Accountability and Quality Control in the Chemical Analysis Laboratory
- E 1601 Practice for Conducting an Interlaboratory Study to Evaluate the Performance of an Analytical Method
- E 1832 Practice for Describing and Specifying a Direct-Current Plasma-Optical Atomic Emission Spectrometer

## 3. Terminology

### 3.1 Definitions:

3.1.1 For definitions of terms used in this guide, refer to Terminology E 135.

### 3.2 Definitions of Terms Specific to This Standard: this Guide:

3.2.1 *background equivalent concentration (BEC), n*—the analyte concentration whose signal is equivalent to the signal generated by the plasma and matrix at the analyte line when the actual analyte concentration is zero.

3.2.2 *detection limit (DL), n*—the lowest detectable smallest quantity equal to three times detectable by the standard deviation of a blank. Types of detection limits are as follows: DCP.

3.2.2.1 *approximate detection limit (ADL), n*—three percent of an estimated detection limit calculated from the background equivalent concentration for an analytical line not background corrected. The ADL is a useful check on daily performance.

3.2.2.1.1 *Discussion*—The IDL and MDL are useful in establishing the low end of the linear range and as a guide in the preparation of calibration and check solutions: concentration.

3.2.2.2 *instrumental detection limit (IDL), n*—For ~~a~~ DCP plasma, the analyte concentration corresponding to three times the standard deviation of the background noise beneath the analyte line on a set of nine consecutive 10-s measurements of the background intensity of the blank. The IDL is useful in characterizing and comparing analytical lines: blank.

3.2.2.3 *method detection limit (MDL), n*—the detection limit measured on the matrix blank. The MDL indicates the effect of the matrix: blank.

3.2.3 *equivalent analyte concentration, n*—the apparent concentration of an interfering element on an analyte, determined by measuring a 1000-mg/L solution of the interfering element at the analyte wavelength: analyte.

3.2.4 *interference, n*—any chemical, physical, or spectral effect that changes the apparent net emission intensity from a spectral line other than a change in concentration of the element emitting that spectral line.

3.2.5 *linear dynamic range, n*—the concentration range from the quantifiable limit to the highest concentration that remains within  $\pm 10\%$  of linearity based on lower concentrations.

3.2.6 *order, spectral, n*—the number of wavelength differences between reflections from successive grooves of a grating or echelle; typically one or two wavelengths for the first or second orders of a grating, 50 or 51 wavelengths for the fiftieth and fifty-first orders from an echelle.

3.2.6.1 *Discussion*—In the DCP echelle, a number of wavelengths appear in two adjacent orders, and these wavelengths usually have similar intensities.

3.2.7 *quantifiable limit (QL)*—the lowest concentration at which the instrument can measure reliably with a defined error and confidence level.

3.2.8 *sensitivity*—the slope of the analytical curve, which is the ratio of the change in emission intensity to the change in concentration.

## 4. Summary of Guide

4.1 Direct current argon plasma atomic emission spectrometers, either simultaneous or sequential, measure elements in solution using atomic emission. Samples and calibration solutions are nebulized and the aerosol is transported to the direct current plasma jet where excitation occurs and characteristic emission spectra are produced. The spectra are dispersed by an echelle grating and cross-dispersed by a prism or grating. They impinge on photomultiplier tubes, whose outputs are interpreted by a computer as emission intensities. Background correction can be used to compensate for some interferences. The computer generates calibration curves and calculates analyte concentration.

## 5. Significance and Use

### 5.1 Accurate application of

<sup>2</sup> For referenced ASTM standards, visit the ASTM website, [www.astm.org](http://www.astm.org), or contact ASTM Customer Service at [service@astm.org](mailto:service@astm.org). For *Annual Book of ASTM Standards*, Vol 14.02, volume information, refer to the standard's Document Summary page on the ASTM website.

*Annual Book of ASTM Standards*, Vol 03.05.

<sup>3</sup> Withdrawn.

5.1 Analyses using direct current plasma spectrometry requires proper preparation of test solutions, accurate calibration, and control of analytical procedure, ~~that are treated broadly in this guide,~~ procedures. ASTM test methods that refer to this guide shall provide specifics on test solutions, calibration, and procedures.

#### ~~5.2 Application of direct~~

5.2 Direct current plasma analysis is primarily concerned with testing materials for compliance with specifications, but may range from qualitative estimations to umpire analysis. These may involve measuring major and minor constituents or trace impurities, or both. This guide suggests some approaches to these different analytical needs.

5.3 This guide assists analysts in developing new methods.

5.4 It is assumed that the users of this guide will be trained analysts capable of performing common laboratory procedures skillfully and safely. It is expected that the work will be performed in a properly equipped laboratory.

5.5 This guide does not purport to define all of the quality assurance parameters necessary for d-c plasma analysis. Analysts should ensure that proper quality assurance procedures are followed, especially those defined by the test method. Refer to Guides E 743 and E 882 or the USEPA Contract Laboratory Program.<sup>4</sup>

## 6. Preparation of Solutions

6.1 Solutions are prepared for different purposes. Not all may be necessary for every test. Prepare only those directed by the method or required to meet specific experimental objectives.

6.2 *Rinse Solution*—Prepare a rinse solution to contain the acids or bases present in the test solution at the same concentration. Prepare a quantity sufficient to clean the end of the sample uptake tubing and to flush the sample introduction system between each determination of calibration solutions and test solutions. Occasionally, an analyte requires a conditioning time in the aspiration/nebulization system of the instrument. In this case, use the test solution as a rinse and allow a sufficient residence time before taking a reading.

6.3 *Reagent Blank Solution*—This solution consists of all reagents and other additions at the same concentration used in preparing the test solution. Carry this solution through the entire sample preparation procedure.

6.4 *Matrix Blank Solution*—Prepare this solution to be as close in composition to the test solution as possible (including dissolution reagents and matrix elements), but omitting the elements to be determined. The matrix elements should be of high purity.

6.5 *Control*—~~Select standard~~ a reference material, certified reference material, or other material of known composition and prepare a solution of it according to ~~as directed in the appropriate~~ test method. This control solution may be used to verify the initial calibration. Analyze the control regularly as a blind sample and use the results for quality control as directed in Guide E 882.

6.6 *Calibration Solutions*—The number and type of these solutions will depend on the method, and on the type of plasma instrument and its microprocessor. Generally, prepare two instrument calibration solutions, one high concentration, and one low concentration or a blank, that bracket the expected concentration range of the sample test solutions. Also prepare at least one other intermediate calibration solution. More may be prepared if the microprocessor can utilize them, especially if the analyte composition of the test solutions are is expected to have cover a large wide range of analyte composition of or if the calibration curve is non-linear. Prepare them calibration solutions by adding aliquots from stock solutions to solutions that are similar ~~in composition to the matrix of~~ the test sample.

6.6.1 Match the matrix of the calibration solutions as closely as possible to that of the test solution in acidity, total solids, reagents, and matrix elements, especially if easily ionized elements are present. Some matrix elements may be eliminated if it can be shown by spike addition or standard additions that the effect on the test solution analytes is insignificant. Use stock solutions or pure elements prepared by a method similar to that used to prepare the test solutions. If the composition of the test solution is unknown to the extent that matched matrix solutions cannot be prepared, or if a sufficiently pure matrix material is not available, refer to the method of standard additions described in 6.7 and 10.6.

NOTE 1—If the instrument is designed to use a blank as the low concentration calibration solution, prepare it the same way as the high concentration calibration solution is prepared, omitting the elements to be determined. Where matched matrix calibration solutions are employed, this will be the matrix blank solution.

6.6.2 *Optimum Calibration Solution Concentration Range* —For calibration in the linear range, the highest concentration should be no more than 85 % of the upper limit of the calibration curve linearity. For an instrument that accepts a low concentration calibration solution, its concentration should be at least four times the method detection limit and above the quantifiable limit.

6.7 *Standard Additions Solutions*—Prepare as directed in either 6.7.1 or 6.7.2 as follows:

6.7.1 Prepare four separate test solutions of the sample. To all but one, add known amounts of the analyte equal to 0.5, 1.0, and 1.5 or 1.0, 2.0, and 3.0 times the expected concentration of the analyte(s) in the test solution. The original analyte concentration must be at or above its quantifiable limit. The final analyte concentration in the highest spike must not be greater than the linear range of the emission line used. Dilute all solutions to the mark and mix. Prepare an equal volume of the reagent blank solution when using 10.6.2.

<sup>4</sup> *Annual Book of ASTM Standards*, Vol. 10.10, 10.10.1, 10.10.2, 10.10.3, 10.10.4, 10.10.5, 10.10.6, 10.10.7, 10.10.8, 10.10.9, 10.10.10, 10.10.11, 10.10.12, 10.10.13, 10.10.14, 10.10.15, 10.10.16, 10.10.17, 10.10.18, 10.10.19, 10.10.20, 10.10.21, 10.10.22, 10.10.23, 10.10.24, 10.10.25, 10.10.26, 10.10.27, 10.10.28, 10.10.29, 10.10.30, 10.10.31, 10.10.32, 10.10.33, 10.10.34, 10.10.35, 10.10.36, 10.10.37, 10.10.38, 10.10.39, 10.10.40, 10.10.41, 10.10.42, 10.10.43, 10.10.44, 10.10.45, 10.10.46, 10.10.47, 10.10.48, 10.10.49, 10.10.50, 10.10.51, 10.10.52, 10.10.53, 10.10.54, 10.10.55, 10.10.56, 10.10.57, 10.10.58, 10.10.59, 10.10.60, 10.10.61, 10.10.62, 10.10.63, 10.10.64, 10.10.65, 10.10.66, 10.10.67, 10.10.68, 10.10.69, 10.10.70, 10.10.71, 10.10.72, 10.10.73, 10.10.74, 10.10.75, 10.10.76, 10.10.77, 10.10.78, 10.10.79, 10.10.80, 10.10.81, 10.10.82, 10.10.83, 10.10.84, 10.10.85, 10.10.86, 10.10.87, 10.10.88, 10.10.89, 10.10.90, 10.10.91, 10.10.92, 10.10.93, 10.10.94, 10.10.95, 10.10.96, 10.10.97, 10.10.98, 10.10.99, 10.10.100, 10.10.101, 10.10.102, 10.10.103, 10.10.104, 10.10.105, 10.10.106, 10.10.107, 10.10.108, 10.10.109, 10.10.110, 10.10.111, 10.10.112, 10.10.113, 10.10.114, 10.10.115, 10.10.116, 10.10.117, 10.10.118, 10.10.119, 10.10.120, 10.10.121, 10.10.122, 10.10.123, 10.10.124, 10.10.125, 10.10.126, 10.10.127, 10.10.128, 10.10.129, 10.10.130, 10.10.131, 10.10.132, 10.10.133, 10.10.134, 10.10.135, 10.10.136, 10.10.137, 10.10.138, 10.10.139, 10.10.140, 10.10.141, 10.10.142, 10.10.143, 10.10.144, 10.10.145, 10.10.146, 10.10.147, 10.10.148, 10.10.149, 10.10.150, 10.10.151, 10.10.152, 10.10.153, 10.10.154, 10.10.155, 10.10.156, 10.10.157, 10.10.158, 10.10.159, 10.10.160, 10.10.161, 10.10.162, 10.10.163, 10.10.164, 10.10.165, 10.10.166, 10.10.167, 10.10.168, 10.10.169, 10.10.170, 10.10.171, 10.10.172, 10.10.173, 10.10.174, 10.10.175, 10.10.176, 10.10.177, 10.10.178, 10.10.179, 10.10.180, 10.10.181, 10.10.182, 10.10.183, 10.10.184, 10.10.185, 10.10.186, 10.10.187, 10.10.188, 10.10.189, 10.10.190, 10.10.191, 10.10.192, 10.10.193, 10.10.194, 10.10.195, 10.10.196, 10.10.197, 10.10.198, 10.10.199, 10.10.200, 10.10.201, 10.10.202, 10.10.203, 10.10.204, 10.10.205, 10.10.206, 10.10.207, 10.10.208, 10.10.209, 10.10.210, 10.10.211, 10.10.212, 10.10.213, 10.10.214, 10.10.215, 10.10.216, 10.10.217, 10.10.218, 10.10.219, 10.10.220, 10.10.221, 10.10.222, 10.10.223, 10.10.224, 10.10.225, 10.10.226, 10.10.227, 10.10.228, 10.10.229, 10.10.230, 10.10.231, 10.10.232, 10.10.233, 10.10.234, 10.10.235, 10.10.236, 10.10.237, 10.10.238, 10.10.239, 10.10.240, 10.10.241, 10.10.242, 10.10.243, 10.10.244, 10.10.245, 10.10.246, 10.10.247, 10.10.248, 10.10.249, 10.10.250, 10.10.251, 10.10.252, 10.10.253, 10.10.254, 10.10.255, 10.10.256, 10.10.257, 10.10.258, 10.10.259, 10.10.260, 10.10.261, 10.10.262, 10.10.263, 10.10.264, 10.10.265, 10.10.266, 10.10.267, 10.10.268, 10.10.269, 10.10.270, 10.10.271, 10.10.272, 10.10.273, 10.10.274, 10.10.275, 10.10.276, 10.10.277, 10.10.278, 10.10.279, 10.10.280, 10.10.281, 10.10.282, 10.10.283, 10.10.284, 10.10.285, 10.10.286, 10.10.287, 10.10.288, 10.10.289, 10.10.290, 10.10.291, 10.10.292, 10.10.293, 10.10.294, 10.10.295, 10.10.296, 10.10.297, 10.10.298, 10.10.299, 10.10.300, 10.10.301, 10.10.302, 10.10.303, 10.10.304, 10.10.305, 10.10.306, 10.10.307, 10.10.308, 10.10.309, 10.10.310, 10.10.311, 10.10.312, 10.10.313, 10.10.314, 10.10.315, 10.10.316, 10.10.317, 10.10.318, 10.10.319, 10.10.320, 10.10.321, 10.10.322, 10.10.323, 10.10.324, 10.10.325, 10.10.326, 10.10.327, 10.10.328, 10.10.329, 10.10.330, 10.10.331, 10.10.332, 10.10.333, 10.10.334, 10.10.335, 10.10.336, 10.10.337, 10.10.338, 10.10.339, 10.10.340, 10.10.341, 10.10.342, 10.10.343, 10.10.344, 10.10.345, 10.10.346, 10.10.347, 10.10.348, 10.10.349, 10.10.350, 10.10.351, 10.10.352, 10.10.353, 10.10.354, 10.10.355, 10.10.356, 10.10.357, 10.10.358, 10.10.359, 10.10.360, 10.10.361, 10.10.362, 10.10.363, 10.10.364, 10.10.365, 10.10.366, 10.10.367, 10.10.368, 10.10.369, 10.10.370, 10.10.371, 10.10.372, 10.10.373, 10.10.374, 10.10.375, 10.10.376, 10.10.377, 10.10.378, 10.10.379, 10.10.380, 10.10.381, 10.10.382, 10.10.383, 10.10.384, 10.10.385, 10.10.386, 10.10.387, 10.10.388, 10.10.389, 10.10.390, 10.10.391, 10.10.392, 10.10.393, 10.10.394, 10.10.395, 10.10.396, 10.10.397, 10.10.398, 10.10.399, 10.10.400, 10.10.401, 10.10.402, 10.10.403, 10.10.404, 10.10.405, 10.10.406, 10.10.407, 10.10.408, 10.10.409, 10.10.410, 10.10.411, 10.10.412, 10.10.413, 10.10.414, 10.10.415, 10.10.416, 10.10.417, 10.10.418, 10.10.419, 10.10.420, 10.10.421, 10.10.422, 10.10.423, 10.10.424, 10.10.425, 10.10.426, 10.10.427, 10.10.428, 10.10.429, 10.10.430, 10.10.431, 10.10.432, 10.10.433, 10.10.434, 10.10.435, 10.10.436, 10.10.437, 10.10.438, 10.10.439, 10.10.440, 10.10.441, 10.10.442, 10.10.443, 10.10.444, 10.10.445, 10.10.446, 10.10.447, 10.10.448, 10.10.449, 10.10.450, 10.10.451, 10.10.452, 10.10.453, 10.10.454, 10.10.455, 10.10.456, 10.10.457, 10.10.458, 10.10.459, 10.10.460, 10.10.461, 10.10.462, 10.10.463, 10.10.464, 10.10.465, 10.10.466, 10.10.467, 10.10.468, 10.10.469, 10.10.470, 10.10.471, 10.10.472, 10.10.473, 10.10.474, 10.10.475, 10.10.476, 10.10.477, 10.10.478, 10.10.479, 10.10.480, 10.10.481, 10.10.482, 10.10.483, 10.10.484, 10.10.485, 10.10.486, 10.10.487, 10.10.488, 10.10.489, 10.10.490, 10.10.491, 10.10.492, 10.10.493, 10.10.494, 10.10.495, 10.10.496, 10.10.497, 10.10.498, 10.10.499, 10.10.500, 10.10.501, 10.10.502, 10.10.503, 10.10.504, 10.10.505, 10.10.506, 10.10.507, 10.10.508, 10.10.509, 10.10.510, 10.10.511, 10.10.512, 10.10.513, 10.10.514, 10.10.515, 10.10.516, 10.10.517, 10.10.518, 10.10.519, 10.10.520, 10.10.521, 10.10.522, 10.10.523, 10.10.524, 10.10.525, 10.10.526, 10.10.527, 10.10.528, 10.10.529, 10.10.530, 10.10.531, 10.10.532, 10.10.533, 10.10.534, 10.10.535, 10.10.536, 10.10.537, 10.10.538, 10.10.539, 10.10.540, 10.10.541, 10.10.542, 10.10.543, 10.10.544, 10.10.545, 10.10.546, 10.10.547, 10.10.548, 10.10.549, 10.10.550, 10.10.551, 10.10.552, 10.10.553, 10.10.554, 10.10.555, 10.10.556, 10.10.557, 10.10.558, 10.10.559, 10.10.560, 10.10.561, 10.10.562, 10.10.563, 10.10.564, 10.10.565, 10.10.566, 10.10.567, 10.10.568, 10.10.569, 10.10.570, 10.10.571, 10.10.572, 10.10.573, 10.10.574, 10.10.575, 10.10.576, 10.10.577, 10.10.578, 10.10.579, 10.10.580, 10.10.581, 10.10.582, 10.10.583, 10.10.584, 10.10.585, 10.10.586, 10.10.587, 10.10.588, 10.10.589, 10.10.590, 10.10.591, 10.10.592, 10.10.593, 10.10.594, 10.10.595, 10.10.596, 10.10.597, 10.10.598, 10.10.599, 10.10.600, 10.10.601, 10.10.602, 10.10.603, 10.10.604, 10.10.605, 10.10.606, 10.10.607, 10.10.608, 10.10.609, 10.10.610, 10.10.611, 10.10.612, 10.10.613, 10.10.614, 10.10.615, 10.10.616, 10.10.617, 10.10.618, 10.10.619, 10.10.620, 10.10.621, 10.10.622, 10.10.623, 10.10.624, 10.10.625, 10.10.626, 10.10.627, 10.10.628, 10.10.629, 10.10.630, 10.10.631, 10.10.632, 10.10.633, 10.10.634, 10.10.635, 10.10.636, 10.10.637, 10.10.638, 10.10.639, 10.10.640, 10.10.641, 10.10.642, 10.10.643, 10.10.644, 10.10.645, 10.10.646, 10.10.647, 10.10.648, 10.10.649, 10.10.650, 10.10.651, 10.10.652, 10.10.653, 10.10.654, 10.10.655, 10.10.656, 10.10.657, 10.10.658, 10.10.659, 10.10.660, 10.10.661, 10.10.662, 10.10.663, 10.10.664, 10.10.665, 10.10.666, 10.10.667, 10.10.668, 10.10.669, 10.10.670, 10.10.671, 10.10.672, 10.10.673, 10.10.674, 10.10.675, 10.10.676, 10.10.677, 10.10.678, 10.10.679, 10.10.680, 10.10.681, 10.10.682, 10.10.683, 10.10.684, 10.10.685, 10.10.686, 10.10.687, 10.10.688, 10.10.689, 10.10.690, 10.10.691, 10.10.692, 10.10.693, 10.10.694, 10.10.695, 10.10.696, 10.10.697, 10.10.698, 10.10.699, 10.10.700, 10.10.701, 10.10.702, 10.10.703, 10.10.704, 10.10.705, 10.10.706, 10.10.707, 10.10.708, 10.10.709, 10.10.710, 10.10.711, 10.10.712, 10.10.713, 10.10.714, 10.10.715, 10.10.716, 10.10.717, 10.10.718, 10.10.719, 10.10.720, 10.10.721, 10.10.722, 10.10.723, 10.10.724, 10.10.725, 10.10.726, 10.10.727, 10.10.728, 10.10.729, 10.10.730, 10.10.731, 10.10.732, 10.10.733, 10.10.734, 10.10.735, 10.10.736, 10.10.737, 10.10.738, 10.10.739, 10.10.740, 10.10.741, 10.10.742, 10.10.743, 10.10.744, 10.10.745, 10.10.746, 10.10.747, 10.10.748, 10.10.749, 10.10.750, 10.10.751, 10.10.752, 10.10.753, 10.10.754, 10.10.755, 10.10.756, 10.10.757, 10.10.758, 10.10.759, 10.10.760, 10.10.761, 10.10.762, 10.10.763, 10.10.764, 10.10.765, 10.10.766, 10.10.767, 10.10.768, 10.10.769, 10.10.770, 10.10.771, 10.10.772, 10.10.773, 10.10.774, 10.10.775, 10.10.776, 10.10.777, 10.10.778, 10.10.779, 10.10.780, 10.10.781, 10.10.782, 10.10.783, 10.10.784, 10.10.785, 10.10.786, 10.10.787, 10.10.788, 10.10.789, 10.10.790, 10.10.791, 10.10.792, 10.10.793, 10.10.794, 10.10.795, 10.10.796, 10.10.797, 10.10.798, 10.10.799, 10.10.800, 10.10.801, 10.10.802, 10.10.803, 10.10.804, 10.10.805, 10.10.806, 10.10.807, 10.10.808, 10.10.809, 10.10.810, 10.10.811, 10.10.812, 10.10.813, 10.10.814, 10.10.815, 10.10.816, 10.10.817, 10.10.818, 10.10.819, 10.10.820, 10.10.821, 10.10.822, 10.10.823, 10.10.824, 10.10.825, 10.10.826, 10.10.827, 10.10.828, 10.10.829, 10.10.830, 10.10.831, 10.10.832, 10.10.833, 10.10.834, 10.10.835, 10.10.836, 10.10.837, 10.10.838, 10.10.839, 10.10.840, 10.10.841, 10.10.842, 10.10.843, 10.10.844, 10.10.845, 10.10.846, 10.10.847, 10.10.848, 10.10.849, 10.10.850, 10.10.851, 10.10.852, 10.10.853, 10.10.854, 10.10.855, 10.10.856, 10.10.857, 10.10.858, 10.10.859, 10.10.860, 10.10.861, 10.10.862, 10.10.863, 10.10.864, 10.10.865, 10.10.866, 10.10.867, 10.10.868, 10.10.869, 10.10.870, 10.10.871, 10.10.872, 10.10.873, 10.10.874, 10.10.875, 10.10.876, 10.10.877, 10.10.878, 10.10.879, 10.10.880, 10.10.881, 10.10.882, 10.10.883, 10.10.884, 10.10.885, 10.10.886, 10.10.887, 10.10.888, 10.10.889, 10.10.890, 10.10.891, 10.10.892, 10.10.893, 10.10.894, 10.10.895, 10.10.896, 10.10.897, 10.10.898, 10.10.899, 10.10.900, 10.10.901, 10.10.902, 10.10.903, 10.10.904, 10.10.905, 10.10.906, 10.10.907, 10.10.908, 10.10.909, 10.10.910, 10.10.911, 10.10.912, 10.10.913, 10.10.914, 10.10.915, 10.10.916, 10.10.917, 10.10.918, 10.10.919, 10.10.920, 10.10.921, 10.10.922, 10.10.923, 10.10.924, 10.10.925, 10.10.926, 10.10.927, 10.10.928, 10.10.929, 10.10.930, 10.10.931, 10.10.932, 10.10.933, 10.10.934, 10.10.935, 10.10.936, 10.10.937, 10.10.938, 10.10.939, 10.10.940, 10.10.941, 10.10.942, 10.10.943, 10.10.944, 10.10.945, 10.10.946, 10.10.947, 10.10.948, 10.10.949, 10.10.950, 10.10.951, 10.10.952, 10.10.953, 10.10.954, 10.10.955, 10.10.956, 10.10.957, 10.10.958, 10.10.959,

6.7.2 Transfer four equal volumes of a test solution to four volumetric flasks of the same size. To all but one, add known amounts of the analyte equal to 0.5, 1.0, and 1.5 or 1.0, 2.0, and 3.0 times the expected concentration of the analyte(s) in the test solution. The final analyte concentration in the test solution should be at or above the quantifiable limit. The final analyte concentration in the highest spike should not exceed the linear dynamic range of the emission line used. Dilute all solutions to the mark and mix. Prepare an equal volume of the reagent blank solution if using 10.6.2. Multiply the final value by a factor to compensate for dilution.

6.8 *Calibration Verification Solution*—Prepare a solution whose concentration is in the midrange in the calibration curve. This may be one of the calibration solutions.

6.9 *Spike Recovery Sample*—Prepare a test solution as directed in the method. Add a spike of the analyte(s) equal to at least 5 times each analyte's quantifiable limit.

6.10 *Quantifiable Limit Solution*—Prepare a solution containing amounts of analyte three to six times the method detection limit or 10 to 20 % of the BEC and matched as closely to the matrix as possible.

## 7. Hazards

7.1 Protect eyes from the intense ultraviolet (UV) radiation of the plasma.

7.2 Follow the manufacturer's recommended operating practices for igniting the plasma and operating the instrument.

7.3 Ensure that HF-resistant materials are used when analyzing solutions containing hydrofluoric acid. Avoid strongly caustic solutions that may cause the ceramic sleeves of the electrodes to fuse.

7.4 For other safety precautions, refer to Practices E 50.

## 8. Characterization of Analytical Lines

### 8.1 Overview:

8.1.1 When setting up a new method, use the recommendations in this section to select a wavelength and evaluate the possible interferences. Measure the approximate linear range, background equivalent concentration, sensitivity, and detection limit experimentally, and ascertain that they are adequate for the analysis. Once these have been established for a specific instrument, periodic confirmation is recommended and especially whenever a change is made in the hardware (for example, transport or detection devices) or optics. Confirm by means analysis of controls or quantifiable limit measurements, or both, that the daily performance of the instrument meets the criteria of the method.

8.1.2 When using an established method for the first time, confirm that freedom from interferences, linearity, detection limit, and sensitivity meet the criteria of the method.

8.1.3 For information on wavelengths, refer to Bosshart,<sup>5</sup> Harrison,<sup>6</sup> or Winge<sup>7</sup>.

8.2 *Interferences*—Several types of interferences may affect measurements. This is especially true for test solutions containing high concentrations of solids or acids or containing elements having intense emission, a large number of emission lines, or high concentrations of easily ionized elements. The presence of interferences should be considered when selecting calibration solutions and the method of analysis. See 8.2.3 for suggestions on how to compensate for interferences.

### 8.2.1 Types of Interference:

8.2.1.1 *Chemical Interferences*—Effects from excitation, molecular compound formation, and solvent vaporization.

8.2.1.2 *Physical Interferences*—Factors that change the rate of sample delivery such as viscosity, surface tension, and reaction with parts of the sample delivery system.

8.2.1.3 *Spectral Interferences*—Spectral line or molecular band overlap from the matrix or solvents, background resulting from continuum radiation, or stray light.

8.2.2 *Diagnosis of Interferences*—Use the following procedures for each new sample matrix:

8.2.2.1 *Comparison with Alternative Method(s) of Analysis*—Use established methods to compare analytical results where possible.

8.2.2.2 *Wavelength Scanning*—If possible, scan the wavelength region near the analyte emission to detect spectral interferences and high background in calibration solutions, test solutions, and solutions containing suspected interfering elements.

8.2.2.3 *Spike Recovery*—Add a known quantity or spike of the analyte equal to at least five times the quantifiable limit. It should be recovered to within  $\pm 2s$  of 100 %, where  $s$  is the standard deviation of at least three replicate measurements. If not, a matrix effect or other interference may be present.

## *USEPA Contract Laboratory Program Statement*

<sup>5</sup> Bosshart, R. E., *Handbook of Work Spectral Line Characteristics for Inorganic Analysis, Multi-Media, Multi-Concentration, SOW 7/88 the DC Plasma Echelle Systems*, Sample Management Office, P.O. Box 818, Alexandria, VA 22313, 1988; ARL Instruments, Sunland, CA 91040.

<sup>6</sup> Bosshart, R. E.,

<sup>6</sup> Harrison, George, R., *Handbook of Spectral Line Characteristics for the DC Plasma Echelle Systems MIT Wavelength Tables, ARL Instruments, Sunland, CA 91040: John Wiley and Sons Inc, New York, NY.*

<sup>7</sup> Harrison, George, R.,

<sup>7</sup> Winge, R. K., Fassel, V. A., Peterson, V. J., and Floyd, M. A., *MIT Wavelength Tables Inductively Coupled Plasma-Atomic Emission Spectroscopy: An Atlas of Spectral Information, John Wiley and Sons Inc, New York, NY; Elsevier Science Publishers, Amsterdam, 1985.*

8.2.2.4 *Serial Dilution*—If the analyte concentration is sufficiently high, analysis of a ten-fold dilution should agree with the expected concentration to within 5 %. If not, a chemical or physical interference may be present.

8.2.2.5 *Equivalent Analyte Concentration*—To obtain a quantitative measurement of the amount of interference from individual elements, measure the equivalent analyte concentration by testing 1000-mg/L solutions of these elements without using background correction.

8.2.3 *Correction for Interference Effects*—If interference effects are indicated, use one or more of the following techniques:

8.2.3.1 *Alternative Wavelength*—Select an analyte emission line free from spectral interferences and having the required sensitivity, linear range, and detection limits.

8.2.3.2 *Background Correction*—If the instrument is equipped for background correction, scan the samples and calibration solutions. Select one or more background correction positions in a level area of the background, preferably at a low point. Refer to instrument operating manuals for specific background correction procedures. ~~Verify~~ Confirm with spikes and controls that background correction is working properly.

8.2.3.3 *Standard Additions*—Prepare the standard addition test solutions by adding known increments of analyte(s) as directed in 6.7. Test as directed in 10.6. In most cases, this will compensate for chemical and physical interferences, but not for ~~background~~ spectral interferences.

8.2.3.4 *Dilution*—If the analyte concentration is sufficiently high, the analyte can be determined on a dilution. A ten-fold dilution may reduce the effects of some interferences, especially matrix enhancement. Prepare different calibration solutions as required. Dilution will not reduce spectral interferences if the analyte and interfering wavelength are close or coincident.

8.2.3.5 *Matrix Matching*—Match the matrix of the calibration solutions to that of the test solution as closely as possible. Ascertain that the matrix is free of the analyte. If the matrix has a well-defined, small amount of analyte, add this to the amount measured by the instrument when the results are calculated or add it to the nominal concentration of the calibration solutions.

8.2.3.6 *Calculated Compensation*—Use equivalent analyte concentrations to correct for known amounts of interfering elements.

8.2.3.7 *Buffers*—Additions of lithium, sodium, potassium, and lanthanum, alone or in combination, have been reported to significantly reduce chemical interferences. Buffer concentrations normally range from 0.1 to 3 % w/v.

8.3 *Linear Dynamic Range*—Prepare a known solution of high concentration, a blank, and others at approximately 0.01, 0.1, 0.3, and 0.7 times the concentration of the high concentration solution. Selection of the high concentration is somewhat arbitrary: it may range from 1000 mg/L or more for a relatively weak emission line to 10 mg/L for an exceedingly strong line.

8.3.1 *Upper Limit*—Calibrate the instrument using the highest concentration calibration solution and the blank. Analyze the other solutions as test solutions, monitoring the calibration solutions for drift and correcting as necessary. If the linearity solutions show a deviation from the expected value of more than 10 %, repeat the process using one of the lower concentrations as the high calibration solution. The upper limit of the linear range is established when the less concentrated solutions deviate from the expected value by less than 10 %.

8.3.2 *Lower Limit*—The lower end of the linear range is the quantifiable limit. ~~NOTE 2—The~~

8.3.3 The linear range can vary with the matrix.

8.4 *Background Equivalent Concentration (BEC)*—Calibrate the dc plasma with a high concentration calibration solution that is approximately 20 times the expected BEC and a blank. Block the entrance slit and measure while in the sample analysis mode. Record the absolute value of the resulting negative concentration as the BEC. The BEC is approximately equal to the intercept of a linear calibration curve.

8.5 *Detection Limits (DL)*—~~Follow the directions in the test method for determining and interpreting detection limit(s). If no instructions are available, determine the detection limit(s) as needed. follows:~~

8.5.1 *Instrument Detection Limit (IDL)*—The IDL is used for characterizing and comparing analytical lines. Calibrate the instrument with a high concentration calibration solution and a blank. The calibration solution should be between three and ten times the BEC. Set the instrument to take nine 10s integrations and display the standard deviation. Measure the blank solution as a test solution three times. Calculate the instrument detection limit as follows:

$$IDL = 3\sqrt{(s_1^2 + s_2^2 + s_3^2)/3} \quad (1)$$

where  $s_1$ ,  $s_2$ , and  $s_3$  are the standard deviations obtained on the three different replications.

~~NOTE 32—The detection limits in Bosshart<sup>5</sup> were calculated as three times the average of the three standard deviations. Pooling the standard deviations yields slightly higher detection limits than those calculated by averaging.~~

8.5.2 *Method Detection Limit (MDL)*—The detection limit for an analyte in a given matrix is often different from what is reported in the literature. For an indication of the effect of the matrix, compare the MDL with the IDL. Follow the instructions of 8.5.1, taking the measurements on the matrix blank. Calculate the MDL as follows:

$$MDL = 3\sqrt{(s_1^2 + s_2^2 + s_3^2)/3} \quad (2)$$

where  $s_1$ ,  $s_2$ , and  $s_3$  are the standard deviations.

8.5.2.1 An approximate MDL can be calculated as 3 % of the matched-matrix BEC or the matched-matrix calibration curve intercept when no background correction is used. ~~NOTE 4—The detection limit for an analyte in a given matrix is often different from what is reported in the literature.~~

8.6 *Quantifiable Limit (QL)*—Measure the quantifiable limit as directed in the method of analysis.

8.6.1 If no directions are given, one approach is to use Eq 21 of Practice E 876:

$$QL = 2ts_c / \sqrt{np} \quad (3)$$

where:

$t$  = multiplier from the student's  $t$  table,

$s_c$  = standard deviation in terms of concentration,

$n$  = number of replicate readings, and

$p$  = specified ratio of the range of the confidence interval to apparent concentration.

8.6.1.1 For example, measure the quantifiable limit solution as a test solution four times, interspersing the measurements with test solutions, calibration verification solutions, and controls. Calculate the quantifiable limit as directed in Eq 21 of Practice E 876, where  $p$  equals 0.3 at the 15 % confidence level and  $t$  for four samples at the 0.05 probability level equals 3.182. This simplifies to:

$$QL = 10.6 s_c \quad (4)$$

where  $s_c$  (in concentration units) is the standard deviation of the four readings. In this example, QL is the level below which the error will be greater than 15 % at the 95 % confidence level.

8.6.2 *Approximate Quantifiable Limit (AQL)*—In the example from 8.6.1, the AQL is equal to 10.6 % of the BEC or 10.6 % of the calibration curve intercept when no background correction is used.

8.6.3 Quantifiable limits should not change drastically (that is, by a factor greater than three) in properly controlled analyses. Quantifiable limits are affected by factors such as instrumental drift, plasma viewing region, background intensity, changes in sensitivity, and drift correction. Exercise caution in assigning significance to a QL measured during an actual sample analysis sequence when it is lower than the AQL unless background correction is being used.

8.6.4 Using background correction often lowers the QL.

8.7 *Sensitivity*—For a linear calibration curve, calculate the slope in terms of change in intensity per unit of change in concentration as follows:

$$\text{slope} = (Y - Y') / (X - X') \quad (5)$$

where:

$X$  = concentration of the high calibration solution,

$X'$  = concentration of the low calibration solution,

$Y$  = emission intensity of the high calibration solution, and

$Y'$  = emission intensity of the low calibration solution.

## 9. Preparation of Apparatus

9.1 *Direct Current Plasma Emission Spectrometer*—Refer to Practice E 1832 for a description of a direct-current plasma emission spectrometer. Select the operating parameters, including entrance and exit slit sizes, gas flow rates, photomultiplier tube voltages, integration time, number of integrations, and other necessary parameters according to the manufacturer's instructions or the particular method of analysis. Turn on the gases, ignite the plasma, and allow it to stabilize for 15 to 30 min while aspirating water or rinse solution. Select the wavelength according to the method being used or determine it experimentally as directed in Section 7. While aspirating a solution of the analyte element, maximize the net emission intensity for the wavelength and plasma position. The net emission intensity is the emission intensity of the analyte minus the emission intensity of the blank solution.

9.1.1 The optimum plasma position is the position where the maximum net signal to background intensity is obtained. The plasma image appears as a "Y". In ascending order based on height above the junction of the three legs there are three regions: just below the excitation region but not in the plasma image (−1); the bottom of the excitation region (zero), and the top of the excitation region (+1). Once the wavelength is optimized, compare the difference between intensities of a calibration standard and blank at the three positions and select the region with the greatest difference. The lower position (−1) is particularly sensitive to changes in the plasma caused by fluctuations in gas pressure or erosion of the electrodes.

9.1.2 For test solutions containing high salt concentrations, optimize the plasma viewing region while aspirating the analyte having a matrix similar to the test solution.

9.1.3 In the multi-element mode some elements are measured at compromise conditions with regard to entrance slit sizes, viewing region, and other parameters.

9.2 *Calibration*—~~Calibrate in accordance with as directed by the manufacturer's instructions and in accordance with as directed~~ by the specific test method if one is available. The instrument's microprocessor generates the calibration coefficients using the emission intensity from the calibration solutions. A curve can also be generated manually as directed in 9.2.3. Either the instrument's coefficients or the manual curve may be used to determine the concentrations of test solutions, other calibration solutions, controls, and verifiers. The following types of calibration may be used:

9.2.1 *Linear Calibration:*

9.2.1.1 *For Test Solutions Less Than 100 Times the Quantifiable Limit*—Calibrate with a high- and low-concentration calibration solution (the low-concentration calibration solution may be a blank.) Enter the calibration solution concentrations.

Analyze the high-concentration calibration solution, the blank, and the verifier or control. Standardize or recalibrate for any of the following reasons: if the high-concentration calibration solution, verifier, or control differ from the expected value by more than 10 % (or other agreed upon value), or if the absolute reading of the blank is greater than the quantifiable limit. Repeat the verification of the updated curve.

9.2.1.2 *For Test Solutions Greater Than 100 Times the Quantifiable Limit*—Calibrate with a high- and low-concentration calibration solution (the low-concentration calibration solution may be a blank.) Enter the calibration solution concentrations. Analyze the high-concentration calibration solution, the blank, and the verifier or control. Standardize or recalibrate for any of the following reasons: if the high-concentration calibration solution, verifier, or control differ from the expected value by more than 5 % (or other agreed upon value), or if the absolute reading of the blank is greater than five times the quantifiable limit. Repeat the verification of the updated curve.

9.2.2 *Non-Linear Calibration*—The concentrations of the calibration solutions should closely bracket those of the test solution. Values of 5 % higher and 5 % lower are recommended. Closely bracketing calibration solutions may also be used in the linear portion of a curve. Use of calibration standard solutions that are within 10 % of one another may result in a high background status message from the instrument panel in some models; this may be ignored. Verify the calibration as directed in 9.2.1.2.

9.2.3 *Multi-Point Calibration*—Set the instrument with a high-calibration solution and a low-calibration solution or blank in accordance with to as directed by the manufacturer’s instructions, recording the emission intensity. Record the emission intensities of at least three other calibration solutions covering the concentration range between the high- and low-calibration solutions, using more if the curve is non linear. Generate the curve with a pocket calculator or graph paper by plotting either raw or net emission intensities of the calibration solutions on the ordinate and the corresponding concentrations on the abscissa. Follow manufacturer’s instructions for instruments that accept multipoint calibration data and generate curves automatically. Verify the calibration as directed in 9.2.1.1 or 9.2.1.2.

## 10. Procedure

10.1 Prepare the test solution as directed by the method of analysis or the analytical plan. The concentration of the analyte should be at least at or above the quantifiable limit. It should be within the linear range of the analytical curve at the wavelength selected, unless the calibration process is performed according to 9.2.2 or 9.2.3. 9.2.2.

10.2 Set the operating parameters, calibrate the spectrometer, and verify the calibration. Flush the system with a rinse solution for 10 s (or an amount of time specified in the method of analysis) between each calibration solution and test solution.

10.3 Analyze one or more test solutions, rinsing between each. Record the concentration. Analyze a high-concentration verifier and quantifiable limit solution after each ten (or fewer) test solutions.

10.3.1 If the verifier differs from the established value by more than 10 % (or some other established control limit), recalibrate or standardize the instrument. Verify the calibration and measure the test solutions again.

10.3.2 If the test solutions are between the quantifiable limit and 30 times the quantifiable limit, and if the quantifiable limit solution deviates from the expected value by more than half the quantifiable limit, recalibrate, standardize, or drift correct.

10.3.3 If the test solutions are between 30 and 100 times the quantifiable limit, and if the quantifiable limit solution deviates from the expected value by more than twice the quantifiable limit, recalibrate, standardize, or drift correct.

10.3.4 If the test solutions are greater than 100 times the quantifiable limit, and if the quantifiable limit solution deviates from the expected value by more than four times the quantifiable limit, recalibrate, standardize, or drift correct.

### 10.4 *Drift Correction:*

10.4.1 A drift in the readings of the verifiers and calibration solutions (both high and low) suggests that the readings of the test solutions have drifted correspondingly. Correcting for this drift using calculations may be helpful for semiquantitative measurements during routine analysis using a well-understood method. Drift correction should not be used for an umpire analysis or when the test solution is so close to a specification limit that the drift correction makes a difference either way. Instead, the instrument should be recalibrated or standardized and the analysis repeated.

10.4.1.1 Test the solutions in the following sequence: high-concentration calibration solution, low-concentration calibration solution (or blank), test solution(s) interspersed with quantifiable limit solutions, high-concentration calibration solution, low-concentration calibration solution. Assign to each reading an integer corresponding to its position in the sequence. For each test solution, calculate a drift-corrected high- and low-calibration solution concentration according to the following:

$$\begin{aligned}
 H_C &= [(H_F - H_I) \times (S_S - I_H)/(F_H - I_H)] + H_I \\
 L_C &= [(L_F - L_I) \times (S_S - I_L)/(F_L - I_L)] + L_I
 \end{aligned}
 \tag{6}$$

where:

$H_C$  = drift-corrected high-calibration solution concentration corresponding to a particular sample test solution at that point in the sequence,

$H_F$  = final concentration reading of the high-concentration calibration solution,

$H_I$  = initial concentration reading of the high-concentration calibration solution,

$L_C$  = drift corrected low-calibration solution concentration corresponding to the same sample test solution at that point in the sequence,

$L_F$  = final concentration reading of the low-concentration calibration solution,

$L_I$  = initial concentration reading of the low-concentration calibration solution,

$S_S$  = integer corresponding to the sample position,

$I_H$  = integer corresponding to the position of the initial reading of the high-concentration calibration solution,

$F_H$  = integer corresponding to the position of the final reading of the high-concentration calibration solution,

$I_L$  = integer corresponding to the position of the initial reading of the low-concentration calibration solution, and

$F_L$  = integer corresponding to the position of the final reading of the low-concentration calibration solution.

10.4.1.2 Calculate the corrected concentration,  $T_C$ , for each sample from the following equation:

$$T_C = (T_O - L_C) \times (H_N - L_N) / (H_C - L_C) + L_N \quad (7)$$

where:

$H_N$  = nominal concentration of the high-calibration solution,

$L_N$  = nominal concentration of the low-calibration solution, and

$T_O$  = observed concentration reading of the sample.

10.4.1.3 This assumes linear drift over time. The times for solution introduction, solution analysis, and for rinsing should be constant. Use of an autosampler is recommended.

10.4.1.4 The number of test and quantifiable limit solutions measured between the two sets of calibration solutions should not exceed ten, not including the calibration solutions.

10.4.1.5 Recalibrate or standardize if the measured concentrations of the calibration solutions exceed by more than 50 % the allowable calibration deviations in 9.2.1.

10.4.1.6 Computer software for some DCP instruments contains a drift-correction protocol that may be used.

10.4.2 *Direct Ratio*—Prepare a number of solutions covering the expected range of the test solutions. Calibrate the instrument and verify the calibration as described in Section 9. Measure the concentration of a test solution, then measure the concentration of the solution closest to its concentration. Calculate the concentration of the test solution according to the following formula:

$$T_C = T_R (C_C / C_R) \quad (8)$$

where:

$T_C$  = corrected concentration of the test solution,

$T_R$  = instrument reading of the test solution concentration,

$C_C$  = nominal concentration of the known solution, and

$C_R$  = instrument reading of the known solution.

10.4.2.1 The direct ratio method is suggested for semiquantitative estimation of analytes in concentrations greater than 50 times the quantifiable limit. For precise analyses or for analyses at concentrations less than 50 times the quantifiable limit, use the drift correction sequence (see 10.4.21.1), where the blank or a low-concentration solution is also monitored and used in the correction.

10.5 *Method of Additions*—Use the method of additions when matrix effects are suspected and matched matrix calibration solutions are unavailable. The concentration of the analyte should be between the quantifiable limit and 50 times the quantifiable limit. (Above that level the test solution can be diluted enough to minimize many of the matrix effects.) Prepare the test solutions as directed in 6.7. Use one of the following methods of analysis:

10.5.1 Calibrate the instrument with a high-concentration calibration solution and a blank. Measure the concentrations of the analyte in the four solutions. Plot the data on graph paper, the added concentration on the abscissa and the corresponding concentration reading on the ordinate. Extrapolate the resulting straight line. The absolute value of the intercept on the  $x$ -axis (abscissa) is the concentration of the analyte in the test solution. Alternatively, use a linear regression program where intensity ( $y$ ) is dependent on concentration ( $x$ ). Solve for  $y = 0$ , that will be the concentration of the analyte. If both matched and non-matrix matched calibrations are used to prepare two curves, the difference in the two slopes is a measure of the matrix effect (enhancement or suppression.)

10.5.2 Calibrate the instrument (within the linear range) using the highest spiked solution as the high-concentration calibration solution and assign it the value of the spike. Use the reagent blank as the low-concentration calibration solution. Aspirate and analyze each of the other three solutions, recording either the concentration reading or three emission intensity readings for each test solution, as well as for the high-concentration calibration solution and the reagent blank. Prepare a curve by plotting the added concentration on the abscissa and the concentration reading or the average relative emission intensity of the standard additions test solutions minus the average emission intensity of the reagent blank on the ordinate. Extrapolate the resulting straight line to the abscissa. The absolute value of the intercept is the concentration of the analyte in the test solution.

10.5.3 The method of standard additions is useful for estimating analytes in difficult matrices but is not recommended for umpire analysis. A limitation of the method of standard additions is that the reagent blank may not correct for sample matrix background levels. Use background correction whenever possible.

10.6 *Internal Standard*:

10.6.1 For simultaneous instruments, an internal standard can compensate for drift and physical interferences. Select an element



that is unlikely to be present in calibration or test solutions, that has a sensitive line not subject to interferences by the matrix, and that does not interfere with the analyte. Ascertain that the internal standard intensity correlates positively with that of the analyte over the expected range of analyte concentrations. Calibrate it at the same time the other analytes are calibrated. Add the same defined amount (at least 100 times its quantifiable limit) of the internal standard to each test solution. Measure it with each test solution. When measuring trace impurities in a single element matrix, one of the matrix wavelengths may be used as an internal standard. More than one internal standard may be used in a test solution to correct different analytes.

10.6.2 For each analyte value, correct for the internal standard reading as follows:

$$C_C = C_R \times I_N / I_R \quad (9)$$

where:

$C_C$  = corrected concentration of the analyte,  
 $C_R$  = reading of the analyte,  
 $I_N$  = nominal value of the internal standard, and  
 $I_R$  = reading of the internal standard.

## 11. Calculation

11.1 Calculate the results, taking into account the weight of the test sample, the volume of the test solution, dilutions, interelement corrections, drift corrections, internal standards, and any other factors. Subtract the readings of the reagent blank from the instrument readings before calculating.

11.2 Carry more significant digits through the calculations than are required for the final result, then round as directed in Practice E 29.

11.3 Report results lower than the quantifiable limit or the scope as “less than” the quantifiable limit determined for that group of test samples or less than the scope of the method. For information on interpreting data and results, refer to Practice E 1601.

## 12. Quality Control/Quality Assurance

12.1 Perform quality control/quality assurance procedures as directed in the method or in Guides E 743 and E 882. Regularly analyze the control as a blind sample to provide a record of control as directed in Guide E 882.

12.2 Maintain required documentation for daily analyses as directed in the method or in Guides E 743 and E 882, including but not limited to instrument calibration and continuing verification, quantifiable limit, test solutions, duplicates, controls, and spikes.

12.3 Maintain the appropriate or required documentation as directed in the method or in Guides E 743 and E 882 for initial methods development and periodic checks, including but not limited to: linear range, detection limits, interferences, BEC, and interelement corrections.

## 13. Keywords

13.1 DCP; dc plasma guide; direct current plasma emission spectroscopy; plasma; plasma operations

*ASTM International takes no position respecting the validity of any patent rights asserted in connection with any item mentioned in this standard. Users of this standard are expressly advised that determination of the validity of any such patent rights, and the risk of infringement of such rights, are entirely their own responsibility.*

*This standard is subject to revision at any time by the responsible technical committee and must be reviewed every five years and if not revised, either reapproved or withdrawn. Your comments are invited either for revision of this standard or for additional standards and should be addressed to ASTM International Headquarters. Your comments will receive careful consideration at a meeting of the responsible technical committee, which you may attend. If you feel that your comments have not received a fair hearing you should make your views known to the ASTM Committee on Standards, at the address shown below.*

*This standard is copyrighted by ASTM International, 100 Barr Harbor Drive, PO Box C700, West Conshohocken, PA 19428-2959, United States. Individual reprints (single or multiple copies) of this standard may be obtained by contacting ASTM at the above address or at 610-832-9585 (phone), 610-832-9555 (fax), or service@astm.org (e-mail); or through the ASTM website (www.astm.org).*